Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	13753	copper with pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:15
S2	127	S1 with window	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:15
<b>S3</b>	60	S2 and wire	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:15
S4	3153	copper with pad and barrier	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:15
S5	1160	S4 and barrier with pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:16
S6	1160	S5 and barrier with pad	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:16
S7	162	S5 and window	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:16
S8	108	S7 and wire	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/05 13:16

S9 107 S8 and (IC integrated adj circuit die wafer semiconductor siliocn chip)	US-PGPUB; OR USPAT; USOCR; EPO; JPO; DERWENT; IBM TDB	ON	2005/08/05 13:16
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